# MSKSEMI 美森科













**ESD** 

VS

TSS

MOV

GDT

PLED

BTA26-600xRG-MS

**Product specification** 





## **FEATURES**

- High current 25 A RMS current Triac
- Low thermal resistance
- High commutation or very high commutation capability

## **APPLICATIONS**

- General purpose motor control circuits
- Phase control operations in light dimmers and motor speed controllers
- Home appliances

#### **APPROVALS**

RoHS: Compliance withHF: Compliance with

## **Reference News**

TOP-3	Schematic Symbol	BTA26-600BRG-MS	BTA26-600CRG-MS
1 2 3	T2(2)> T1(1) G(3)	MSKSEMI BTA26-600BRG MS***	MSKSEMI BTA26-600CRG MS***

## THE MAIN PARAMETERS

Symbol	Parameter	Value	Unit
L <sub>T(RMS)</sub>	RMS on-state current	25	А
$V_{DRM}$	Off-state repetitive peak voltage	600	V
V <sub>TM</sub>	On-state voltage	1.5	V



## **ABSOLUTE MAXIMUM RATINGS**

Parameter	Symbol	Value	Unit
Repetitive peak off-state voltage (T <sub>j</sub> =25℃)	$V_{DRM}$	600	V
Repetitive peak reverse voltage (Tj=25℃)	$V_{RRM}$	600	V
RMS on-state current (T <sub>c</sub> =95°C)	I <sub>T(RMS)</sub>	25	
Non repetitive surge peak on-state current (full cycle, F=50Hz)	I <sub>TSM</sub>	250	А
Pt value for fusing (tp=10ms)	<b> </b> 2t	340	A <sup>2</sup> S
Critical rate of rise of on-state current (I <sub>G</sub> =2*I <sub>GT</sub> )	dl/dt	50	A/µs
Peak gate current	<b>I</b> <sub>GM</sub>	4	А
Average gate power dissipation	$P_{G(AV)}$	1	W
Storage junction temperature range	T <sub>STG</sub>	-40~+150	$^{\circ}\mathrm{C}$
Operating junction temperature range	T <sub>j</sub>	-40~+125	C

# **ELECTRICAL CHARACTERISTICS** (T<sub>j</sub>=25 $^{\circ}$ C unless otherwise specified)

Symbol Test Condition		Quadrant	Value		Hoit	
Symbol	rest Condition	Quadrant	В	С	Unit	
l <sub>GT</sub>	$V_D=12V,R_L=33\Omega$	I - II-III	≤50	≤35	mA	
$V_{\rm GT}$			≤1.5		V	
$V_{\sf GD}$	$V_D = V_{DRM}, R_L = 3.3 K\Omega, T_j = 125 ^{\circ}C$		≥0.2		V	
I <sub>H</sub>	I <sub>T</sub> =100mA		≤80	≤60		
		I - III	≤90	≤70	mA	
I <sub>L</sub>	I <sub>G</sub> =1.2I <sub>GT</sub>	II	≤100	≤80		
dV <sub>D</sub> /dt	$V_{D} = 67\%V_{DRM}, T_{j} = 125\%$		≥1500	≥1000	V/µs	
$V_{TM}$	I <sub>τм</sub> =35A,tp=380μs		≤1.5		V	
I <sub>DRM</sub>	\/ -\/ \/ \/ -\/	T <sub>j</sub> =25℃	≤5		uA	
I <sub>RRM</sub>	$V_D = V_{DRM}$ , $V_R = V_{RRM}$	T <sub>j</sub> =125℃	≤3		mA	

# THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R <sub>th(j-c)</sub>	Junction to case(AC)	0.67	°C/W



# PARAMETER CHARACTERISTIC CURVE

FIG.1 Maximum power dissipation versus RMS on-state current

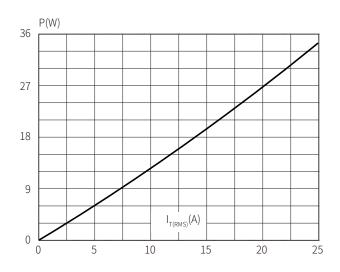


FIG.2: RMS on-state current versus case temperature

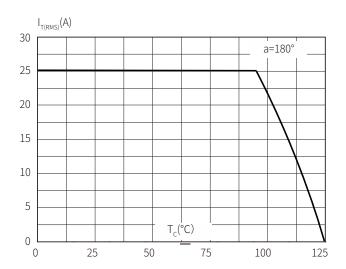


FIG.3: Surge peak on-state current versus number of cycles

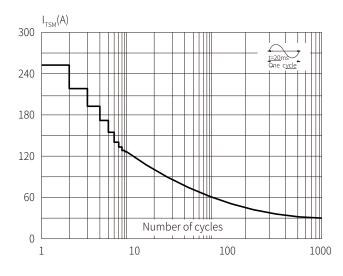


FIG.4 On-state characteristics (maximum values)

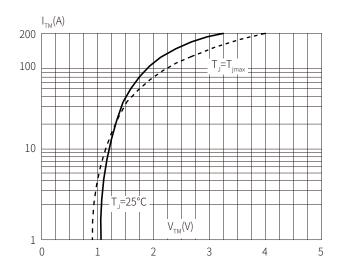




FIG.5: Non-repetitive surge peak on-state currentfor a sinusoidal pulse with width tp<20ms and corresponding value of I²t (dI/dt < 50A/μs)

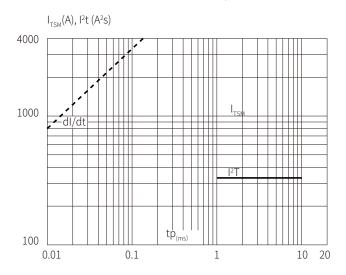


FIG.6 Relative variations of gate trigger current versus junction temperature

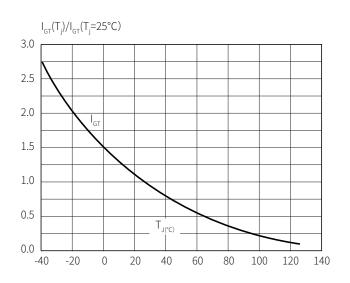


FIG.7 Relative variations of holding current versus junction temperature

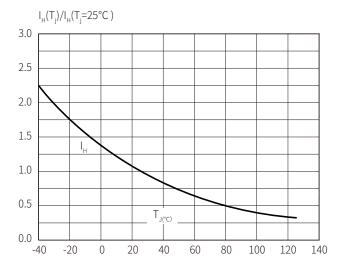
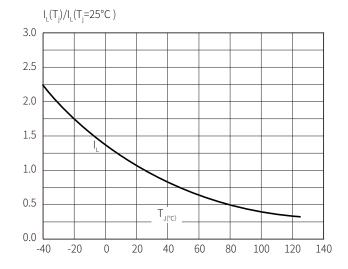
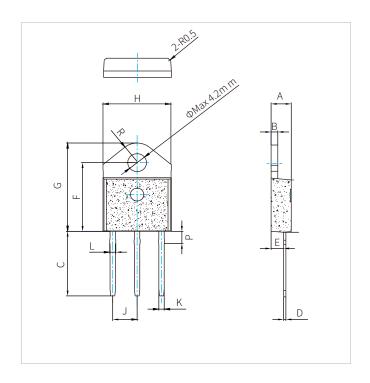


FIG.8 Relative variations of atching current versus junction temperature





# **TOP-3 PACKAGE MECHANICAL DATA**



	Dimensions					
Ref.	ı	/lillimete	rs		Inches	
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	4.30		4.70	0.169		0.185
В	1.40		1.60	0.056		0.063
С	14.35		15.60	0.565		0.614
D	0.50		0.70	0.020		0.028
Е	2.70		2.90	0.106		0.114
F	15.		16.	0.618		0.654
G	7020.		6021.	0.803		0.831
Н	4015.		1015.	0.591		0.614
J	00		60	0.213		0.222
К	5.40		5.65	0.043		0.055
L	1.10		1.40	0.047		0.059
Р	1.20		1.50	0.110		0.150
R	2.80	4.35	3.80		0.171	

# **Order information**

P/N	PKG	QTY
BTA26-600BRG-MS	TOP-3	480PCS
BTA26-600CRG-MS	TOP-3	480PCS



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